

**MRS**

# BULLETIN

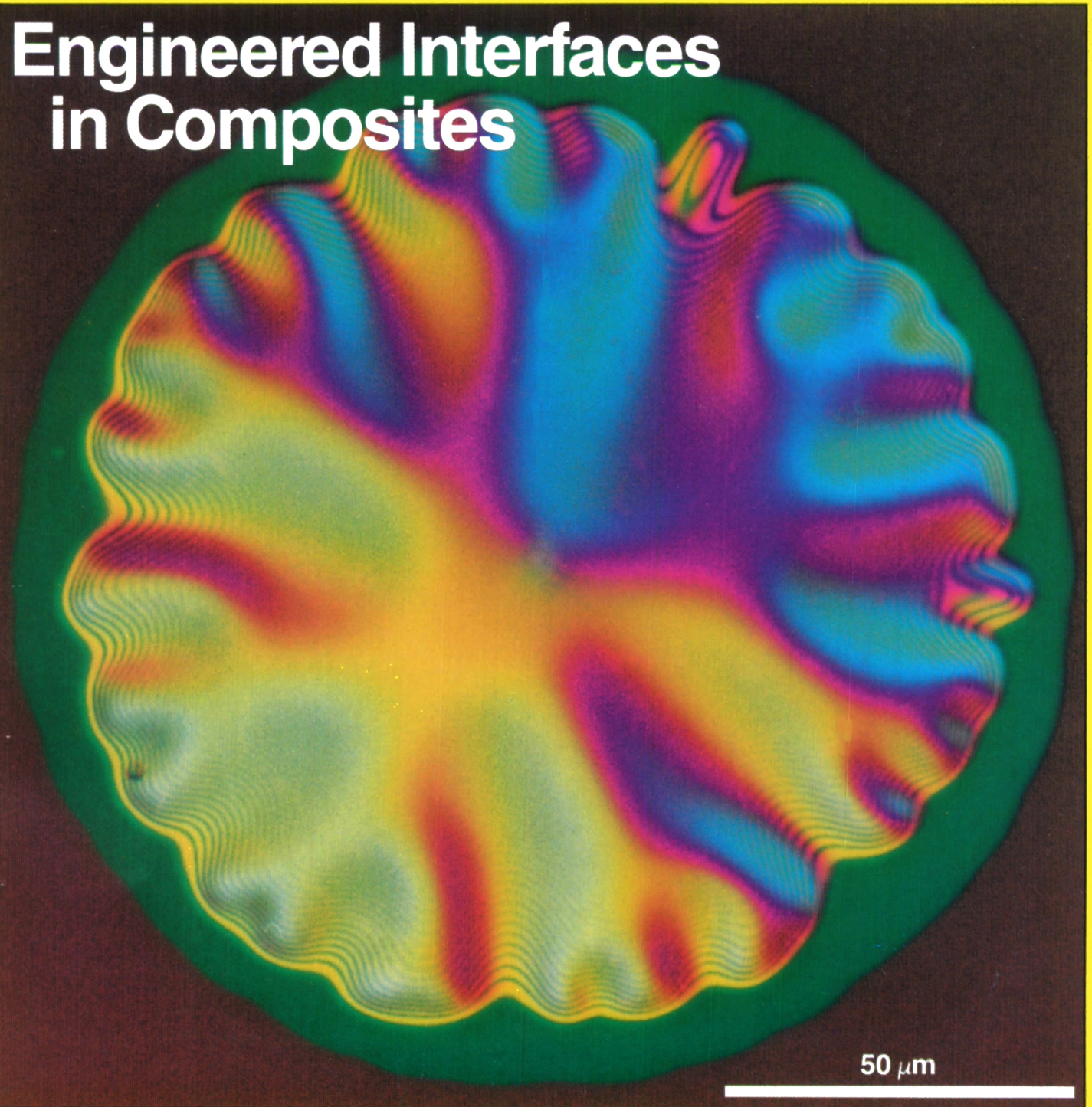
Serving the International  
Materials Research Community

A Publication of the Materials Research Society

April 1991, Volume XVI, No.4



## Engineered Interfaces in Composites



50  $\mu\text{m}$

# A NEW CLUSTER IS BORN



## **General Ionex acquired by High Voltage Engineering Europa B.V.**

In December 1987 High Voltage Engineering Europa B.V. (HVEE) acquired Dowlish Developments Ltd (DD), an accelerator tube manufacturer located in the United Kingdom.

On April 10, 1989, HVEE purchased the General Ionex Analytical Product Group from Genus Inc. based in the United States.

Through this acquisition HVEE positions itself as the largest and most diverse manufacturer of particle accelerators for the scientific and industrial research communities.

The acquired General Ionex (GI) product lines, which include the Tandetron accelerator systems and Model 4175 RBS Analyser, will be manufactured in HVEE's new, well-equipped facility in Amersfoort, The Netherlands.

World wide marketing of all products from HVEE, DD and GI will originate from HVEE Amersfoort with sales and service offices in the USA, Europe and Japan.

After addition of the newly acquired products HVEE's product lines include:

– *Ion Accelerator Systems*

- Air insulated accelerators up to 500 kV
- Single ended Van de Graaff accelerators up to 4 MV
- Tandem Tandetron accelerators up to 3 MV/TV

– *Research ion implanters*

- Beam energies 10 keV-9 MeV and higher

– *Systems for ion beam analysis*

- Systems for RBS, PIXE, PIGE, NRA, ERD, MACS and MEIS

– *Components*

- HV power supplies, electron and ion accelerator tubes, ion sources beamline components, beam monitoring equipment, UHV sample manipulators, etc.

For further information on this transaction and product literature please contact HVEE in Amersfoort/NL.

Please visit Booth No. 504 at the MRS Show in Anaheim, CA, April 30-May 2, 1991.

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**More  
Energy for Research**

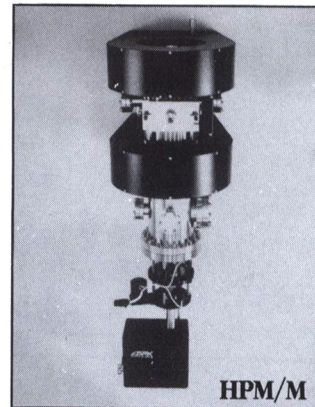
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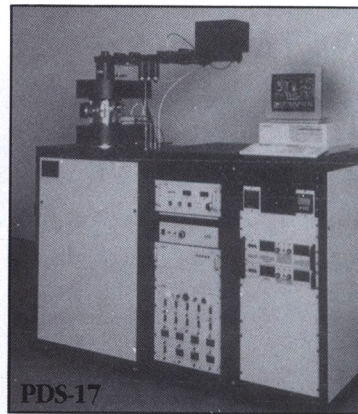
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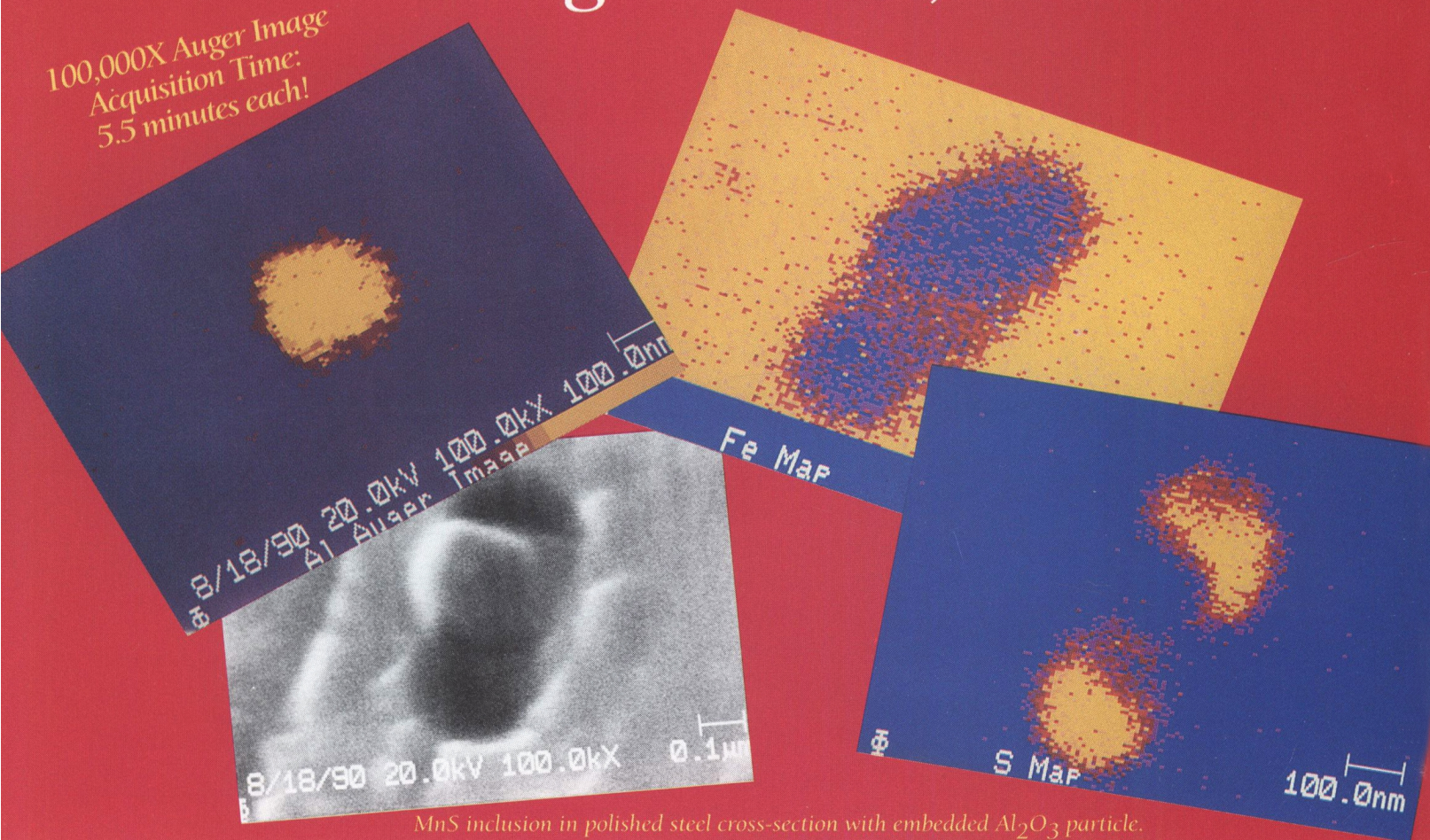
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## **ENGINEERED INTERFACES IN COMPOSITES**

- 27 Designing Interfaces**  
J.A. Cornie, Guest Editor
- 32 Designing Interfaces in  
Inorganic Matrix  
Composites**  
J.A. Cornie, A.S. Argon, and  
V. Gupta
- 39 An Evaluation of the  
Interface Tensile  
Strength-Toughness  
Relationship**  
V. Gupta
- 46 Theoretical and  
Experimental Studies of  
Ceramic: Metal Wetting**  
K.C. Russell, S.-Y. Oh, and  
A. Figueredo
- 53 Geometrical Origins of  
Interfacial Strength**  
M.E. Eberhart, D.P. Clougherty,  
and J.N. Louwen
- 59 Fiber Coatings Derived from  
Molecular Precursors**  
H.E. Fischer, D.J. Larkin, and  
L.V. Interrante

## **MRS NEWS**

- 68 MRS Committees Focus on  
Planning, Outreach to  
Materials Community**
- 79 International Field Emission  
Society Becomes MRS  
Affiliated Organization**

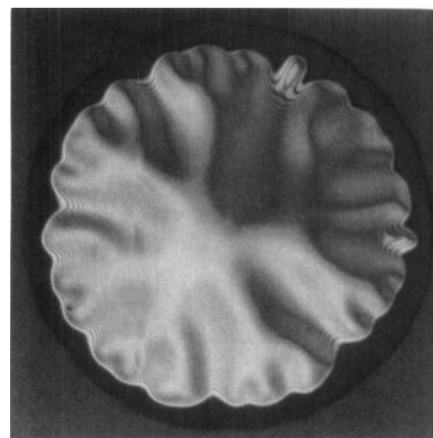
## **INTERNATIONAL UNION OF MATERIALS RESEARCH SOCIETIES**

- 66 Charting a Course for the  
International Union of  
Materials Research  
Societies**
- 67 Materials Research Society  
of India Holds Second  
Annual General Meeting**

## **DEPARTMENTS**

- 7 Letter from the President**
- 11 Material Matters**
- 14 Resources**
- 17 Research/Researchers**
- 21 Editor's Choice**
- 22 From Washington**
- 74 Advertisers in This Issue**
- 81 Upcoming Conferences**
- 84 Historical Note**
- 86 Journal of Materials  
Research**
- 88 Book Reviews**
- 90 Calendar**
- 94 Classified**

**ON THE COVER:** A large buckled blister in a SiC coating in the process of undergoing delamination from a Si crystal viewed with a Nomarski interference contrast mode of microscopy. The coating was deposited by H.S. Landis as part of work for his Doctorate of Science dissertation at MIT. The photo comes from "Intrinsic Toughness of Interfaces Between SiC Coatings and Substrates of Si or C Fibers" by A.S. Argon, V. Gupta, H.S. Landis, and J.A. Cornie, *Journal of Materials Science*, 24 (1989) p. 1207-1218.



## About the Materials Research Society

The Materials Research Society (MRS), a nonprofit scientific association founded in 1973, promotes interdisciplinary goal-oriented basic research on materials of technological importance. Membership in the Society includes more than 10,000 scientists, engineers, and research managers from industrial, government, and university research laboratories in the United States and more than 40 countries.

The Society's interdisciplinary approach differs from that of single-discipline professional societies because it promotes information exchange across the many technical fields touching materials development. MRS sponsors two major international annual meetings encompassing approximately 50 topical symposia, and also sponsors numerous single-topic scientific meetings. The Society recognizes professional and technical excellence, conducts short courses, and fosters technical interaction in local geographic regions through Sections and University Chapters.

MRS participates in the international arena of materials research through the International Union of Materials Research Societies (IUMRS). MRS is an affiliate of the American Institute of Physics.

MRS publishes symposium proceedings, *MRS Bulletin*, *Journal of Materials Research*, and other publications related to current research activities.

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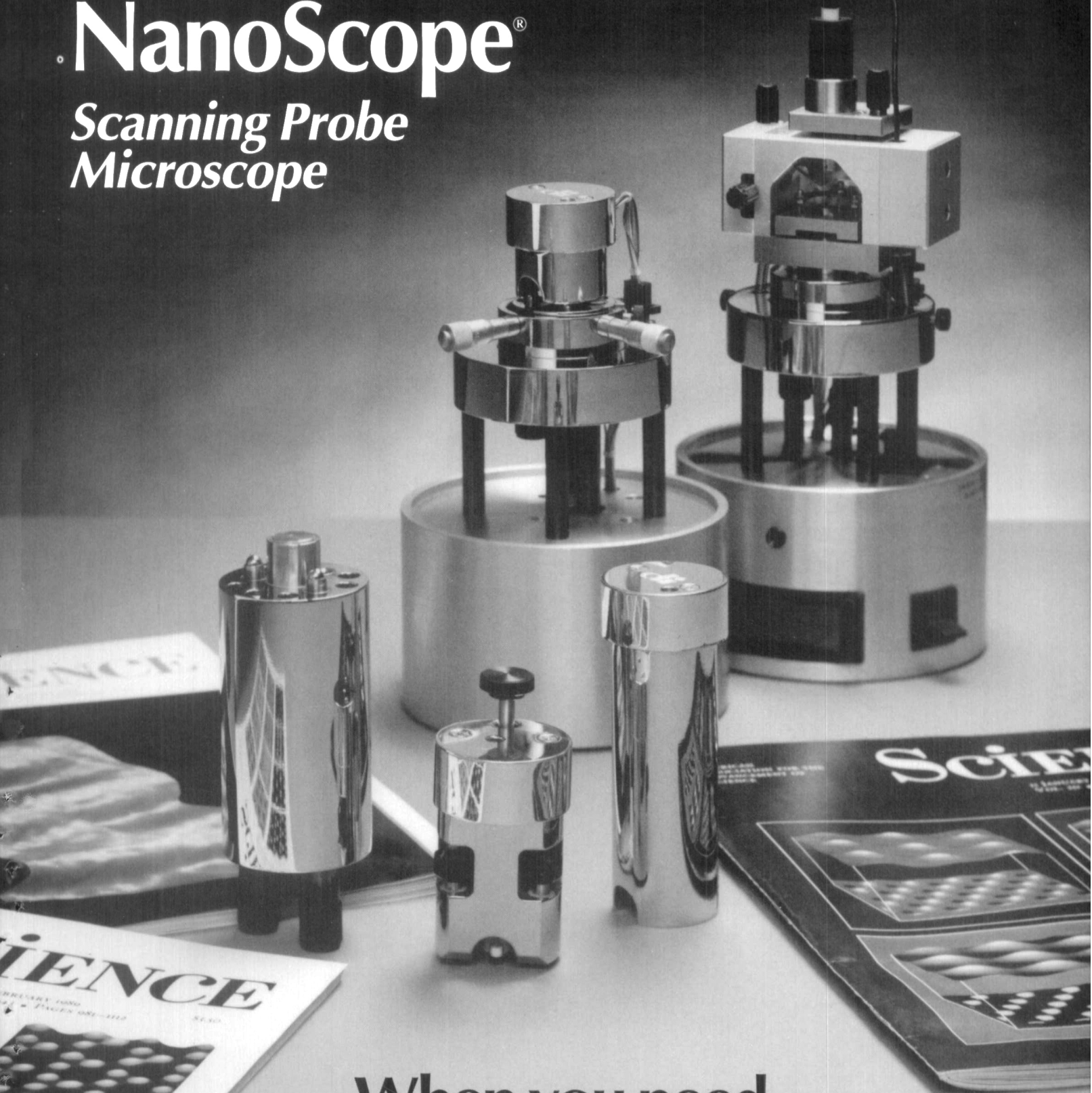
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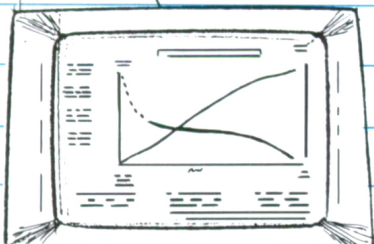
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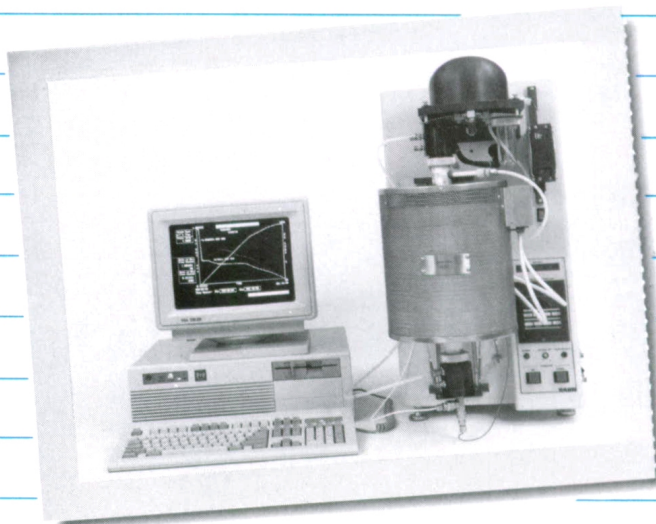
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